# MTM86727

### Silicon N-channel MOS FET (FET) Silicon epitaxial planar type (SBD)

For DC-DC converter circuits For switching circuits

### Overview

MTM86727 is the composite MOS FET (N-channel MOS FET and schottky barrier diode) that is highly suitable for DC-DC converter and other switching circuits.

### Features

- Built-in schottky barrier diode:  $V_R = 20 V$ ,  $I_F = 800 mA$
- Low ON resistance:  $R_{on} = 80 \text{ m}\Omega (V_{GS} = 4.0 \text{ V})$
- Low short-circuit input capacitance (common source):  $C_{iss} = 280 \text{ pF}$
- Small package: WSSMini6-F1 (1.6 mm × 1.6 mm × 0.5 mm)
- Low drive voltage: 2.5 V drive

### Absolute Maximum Ratings $T_a = 25^{\circ}C$

	Parameter	Symbol	Rating	Unit
FET	Drain-source surrender voltage	V <sub>DSS</sub>	20	V
	Gate-source surrender voltage	V <sub>GSS</sub>	±10	V
	Drain current	ID	2.2	S A
	Peak drain current	I <sub>DP</sub>	8.0	А
	Channel temperature	T <sub>ch</sub>	150	°C
	Storage temperature	T <sub>stg</sub>	-55 to +150	°C
	Reverse voltage	VR	20	V
	Forward current (Average)	I <sub>F(AV)</sub>	800	mA
SBD	Non-repetitive peak reverse surge voltage *1	I <sub>FSM</sub>	3	A
	Junction temperature	Tj	125	°C
	Storage temperature	T <sub>stg</sub>	-55 to +125	°C
Overall	Total power dissipation *2	P <sub>D</sub>	540	mW

Note) \*1: 50 Hz sine wave 1 cycle (Non-repetitive peak current) \*2: Measuring on ceramic substrate at 40 mm × 38 mm × 0.2 mm

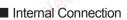
 $P_{\rm D}$  absolute maximum rating without a heat shink: 150 mW

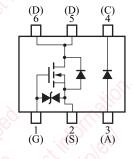
- Package
- Code
- WSSMini6-F1
- Pin Name
  - 1. Gate
  - 2. Source 5. Drain

3. Anode 6. Drain

4. Cathode

Marking Symbo: JE





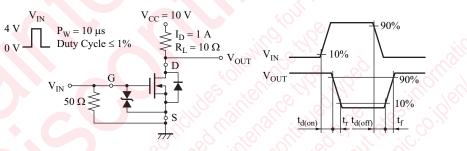
### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

• FET

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source surrender voltage	V <sub>DSS</sub>	$I_D = 1 \text{ mA}, V_{GS} = 0$	20			V
Drain-source cutoff current	I <sub>DSS</sub>	$V_{\rm DS} = 20  {\rm V},  {\rm V}_{\rm GS} = 0$			1.0	μΑ
Gate-source cutoff current	I <sub>GSS</sub>	$V_{GS} = \pm 8 V, V_{DS} = 0$			±10	μΑ
Gate threshold voltage	$V_{\mathrm{TH}}$	$I_D = 1.0 \text{ mA}, V_{DS} = 10 \text{ V}$	0.4	0.85	1.3	V
Drain-source ON resistance 1	R <sub>DS(on)</sub> 1	$I_D = 1 \text{ A}, V_{GS} = 4.0 \text{ V}$		80	105	mΩ
Drain-source ON resistance 2	R <sub>DS(on)</sub> 2	$I_D = 0.5 \text{ A}, V_{GS} = 2.5 \text{ V}$		100	150	mΩ
Forward transfer admittance	Y <sub>fs</sub>	$I_D = 1.0 \text{ A}, V_{DS} = 10 \text{ V}$	3.0			S
Short-circuit input capacitance (Common source)	C <sub>iss</sub>			280		pF
Short-circuit output capacitance (Common source)	C <sub>oss</sub>	$\frac{C_{oss}}{C_{rss}} V_{DS} = 10 V, V_{GS} = 0, f = 1 MHz$		18		pF
Reverse transfer capacitance (Common source)	C <sub>rss</sub>			17	<u>ک</u> .	pF
Turn-on delay time *	t <sub>d(on)</sub>			5		ns
Rise time *	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, V_{GS} = 0 \text{ V} \text{ to } 4 \text{ V}, I_D = 1 \text{ A}$	e la	8		ns
Turn-off delay time *	t <sub>d(off)</sub>	$V_{DD} = 6 V, V_{GS} = 4 V \text{ to } 0 V, I_D = 1 A$	1900	20		ns
Fall time *	t <sub>f</sub>	$v_{\rm DD} = 0 v, v_{\rm GS} = 4 v t 0 0 v, t_{\rm D} = 1 \text{ A}$	3	18		ns

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*: Test circuit



#### • SBD

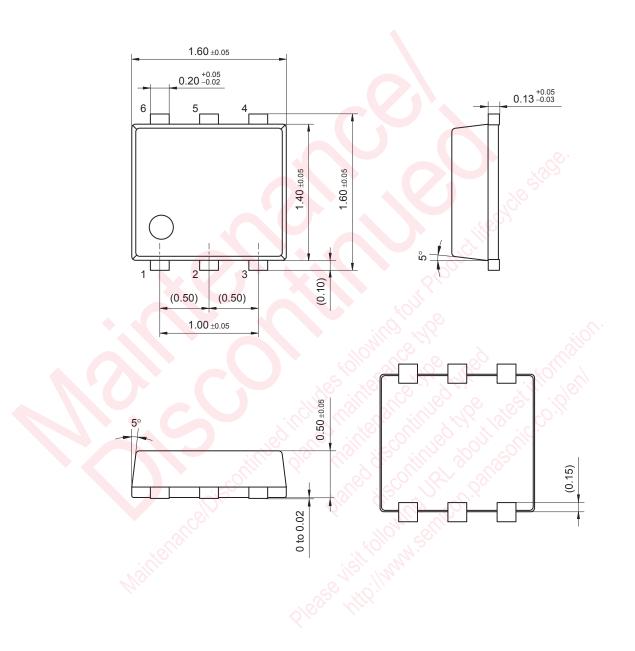
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	V <sub>F</sub>	$I_F = 800 \text{ mA}$	, <i>?</i> ~		0.47	V
Reverse current	I <sub>R</sub>	V <sub>R</sub> =20 V			80	μΑ

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

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## WSSMini6-F1

Unit: mm



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